

APPLICATION DATA SHEET

Electronic Version v14

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| Title of Invention | INCREASE PRODUCTIVITY AT WAFER TEST USING PROBE RETEST DATA ANALYSIS |
| Application Type : regular, utility Attorney Docket Number : BUR920040137US1 | |
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| Attorney Information: practitioner(s) at Customer Number: 29154  as my attorney(s) or agent(s) to prosecute the application identified above, and to transact all business in the United States Patent and Trademark Office connected therewith. | |

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